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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	76500
Number of Logic Elements/Cells	979200
Total RAM Bits	55296000
Number of I/O	720
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	1924-BBGA, FCBGA
Supplier Device Package	1926-FCBGA (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7vx980t-l2ff1926e

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT} , V_{CCBRAM} , V_{CCAUX} , V_{CCAUX_IO} , and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX} , V_{CCAUX_IO} , and V_{CCO} have the same recommended voltage levels then they can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than $T_{VCCO2VCCAUX}$ for each power-on/off cycle to maintain device reliability levels.
- The $T_{VCCO2VCCAUX}$ time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTX/GTH transceivers is V_{CCINT} , $V_{MGTAVCC}$, $V_{MGTAVTT}$ OR $V_{MGTAVCC}$, V_{CCINT} , $V_{MGTAVTT}$. There is no recommended sequencing for $V_{MGTAVCAUX}$. Both $V_{MGTAVCC}$ and V_{CCINT} can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from $V_{MGTAVTT}$ can be higher than specifications during power-up and power-down.

- When $V_{MGTAVTT}$ is powered before $V_{MGTAVCC}$ and $V_{MGTAVTT} - V_{MGTAVCC} > 150$ mV and $V_{MGTAVCC} < 0.7$ V, the $V_{MGTAVTT}$ current draw can increase by 460 mA per transceiver during $V_{MGTAVCC}$ ramp up. The duration of the current draw can be up to $0.3 \times T_{MGTAVCC}$ (ramp time from GND to 90% of $V_{MGTAVCC}$). The reverse is true for power-down.
- When $V_{MGTAVTT}$ is powered before V_{CCINT} and $V_{MGTAVTT} - V_{CCINT} > 150$ mV and $V_{CCINT} < 0.7$ V, the $V_{MGTAVTT}$ current draw can increase by 50 mA per transceiver during V_{CCINT} ramp up. The duration of the current draw can be up to $0.3 \times T_{VCCINT}$ (ramp time from GND to 90% of V_{CCINT}). The reverse is true for power-down.

LVDS DC Specifications (LVDS_25)

The LVDS standard is available in the HR I/O banks.

Table 12: LVDS_25 DC Specifications⁽¹⁾

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply voltage		2.375	2.500	2.625	V
V_{OH}	Output High voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	–	–	1.675	V
V_{OL}	Output Low voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.700	–	–	V
V_{ODIFF}	Differential output voltage ($Q - \bar{Q}$), Q = High ($Q - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output common-mode voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential input voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input common-mode voltage		0.300	1.200	1.425	V

Notes:

1. Differential inputs for LVDS_25 can be placed in banks with V_{CCO} levels that are different from the required level for outputs. Consult the 7 Series FPGAs SelectIO Resources User Guide ([UG471](#)) for more information.

LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks.

Table 13: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply voltage		1.710	1.800	1.890	V
V_{OH}	Output High voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	–	–	1.675	V
V_{OL}	Output Low voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.825	–	–	V
V_{ODIFF}	Differential output voltage ($Q - \bar{Q}$), Q = High ($Q - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output common-mode voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential input voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	Common-mode input voltage = 1.25V	100	350	600	mV
V_{ICM}	Input common-mode voltage	Differential input voltage = ± 350 mV	0.300	1.200	1.425	V

Notes:

1. Differential inputs for LVDS can be placed in banks with V_{CCO} levels that are different from the required level for outputs. Consult the 7 Series FPGAs SelectIO Resources User Guide ([UG471](#)) for more information.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T_{IOPI}			T_{IOOP}			T_{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1		
LVTTL_S4	1.31	1.42	1.64	3.77	3.90	4.00	4.53	4.76	4.99	ns	
LVTTL_S8	1.31	1.42	1.64	3.50	3.64	3.73	4.26	4.50	4.72	ns	
LVTTL_S12	1.31	1.42	1.64	3.49	3.62	3.72	4.25	4.48	4.71	ns	
LVTTL_S16	1.31	1.42	1.64	3.03	3.17	3.26	3.79	4.03	4.25	ns	
LVTTL_S24	1.31	1.42	1.64	3.25	3.39	3.48	4.01	4.25	4.47	ns	
LVTTL_F4	1.31	1.42	1.64	3.22	3.36	3.45	3.98	4.22	4.44	ns	
LVTTL_F8	1.31	1.42	1.64	2.71	2.84	2.93	3.47	3.70	3.92	ns	
LVTTL_F12	1.31	1.42	1.64	2.69	2.82	2.92	3.45	3.68	3.91	ns	
LVTTL_F16	1.31	1.42	1.64	2.57	2.85	3.15	3.33	3.71	4.14	ns	
LVTTL_F24	1.31	1.42	1.64	2.41	2.64	2.89	3.17	3.50	3.88	ns	
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	1.36	1.47	1.55	2.12	2.33	2.54	ns	
MINI_LVDS_25	0.68	0.70	0.79	1.36	1.47	1.55	2.12	2.33	2.54	ns	
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	1.83	2.02	2.20	2.59	2.88	3.19	ns	
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	1.36	1.48	1.55	2.12	2.34	2.54	ns	
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	1.36	1.49	1.58	2.12	2.35	2.57	ns	
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	1.43	1.54	1.60	2.19	2.40	2.59	ns	
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	2.71	3.08	3.52	3.47	3.94	4.51	ns	
HSUL_12	0.63	0.64	0.71	1.77	1.90	2.00	2.53	2.76	2.99	ns	
DIFF_HSUL_12	0.58	0.61	0.70	1.55	1.68	1.78	2.31	2.54	2.77	ns	
HSTL_I_S	0.61	0.64	0.73	1.55	1.69	1.80	2.31	2.55	2.79	ns	
HSTL_II_S	0.61	0.64	0.73	1.21	1.34	1.43	1.97	2.20	2.42	ns	
HSTL_I_18_S	0.64	0.67	0.76	1.28	1.39	1.45	2.04	2.25	2.44	ns	
HSTL_II_18_S	0.64	0.67	0.76	1.18	1.31	1.40	1.94	2.17	2.39	ns	
DIFF_HSTL_I_S	0.63	0.67	0.77	1.42	1.54	1.61	2.18	2.40	2.60	ns	
DIFF_HSTL_II_S	0.63	0.67	0.77	1.15	1.24	1.27	1.91	2.10	2.26	ns	
DIFF_HSTL_I_18_S	0.65	0.69	0.78	1.27	1.38	1.43	2.03	2.24	2.42	ns	
DIFF_HSTL_II_18_S	0.65	0.69	0.78	1.14	1.23	1.26	1.90	2.09	2.25	ns	
HSTL_I_F	0.61	0.64	0.73	1.10	1.19	1.23	1.86	2.05	2.22	ns	

Table 19: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1		
HSTL_II_F	0.61	0.64	0.73	1.05	1.18	1.28	1.81	2.04	2.27	ns	
HSTL_I_18_F	0.64	0.67	0.76	1.05	1.18	1.28	1.81	2.04	2.27	ns	
HSTL_II_18_F	0.64	0.67	0.76	1.03	1.14	1.23	1.79	2.00	2.22	ns	
DIFF_HSTL_I_F	0.63	0.67	0.77	1.09	1.18	1.22	1.85	2.04	2.21	ns	
DIFF_HSTL_II_F	0.63	0.67	0.77	1.02	1.11	1.14	1.78	1.97	2.13	ns	
DIFF_HSTL_I_18_F	0.65	0.69	0.78	1.08	1.17	1.21	1.84	2.03	2.20	ns	
DIFF_HSTL_II_18_F	0.65	0.69	0.78	1.01	1.10	1.13	1.77	1.96	2.12	ns	
LVCMOS33_S4	1.31	1.40	1.60	3.77	3.90	4.00	4.53	4.76	4.99	ns	
LVCMOS33_S8	1.31	1.40	1.60	3.49	3.62	3.72	4.25	4.48	4.71	ns	
LVCMOS33_S12	1.31	1.40	1.60	3.05	3.18	3.28	3.81	4.04	4.27	ns	
LVCMOS33_S16	1.31	1.40	1.60	3.06	3.43	3.88	3.82	4.29	4.87	ns	
LVCMOS33_F4	1.31	1.40	1.60	3.22	3.36	3.45	3.98	4.22	4.44	ns	
LVCMOS33_F8	1.31	1.40	1.60	2.71	2.84	2.93	3.47	3.70	3.92	ns	
LVCMOS33_F12	1.31	1.40	1.60	2.57	2.85	3.15	3.33	3.71	4.14	ns	
LVCMOS33_F16	1.31	1.40	1.60	2.44	2.69	2.96	3.20	3.55	3.95	ns	
LVCMOS25_S4	1.08	1.16	1.32	3.08	3.22	3.31	3.84	4.08	4.30	ns	
LVCMOS25_S8	1.08	1.16	1.32	2.85	2.98	3.07	3.61	3.84	4.06	ns	
LVCMOS25_S12	1.08	1.16	1.32	2.44	2.57	2.67	3.20	3.43	3.66	ns	
LVCMOS25_S16	1.08	1.16	1.32	2.79	2.92	3.01	3.55	3.78	4.00	ns	
LVCMOS25_F4	1.08	1.16	1.32	2.71	2.84	2.93	3.47	3.70	3.92	ns	
LVCMOS25_F8	1.08	1.16	1.32	2.14	2.28	2.37	2.90	3.14	3.36	ns	
LVCMOS25_F12	1.08	1.16	1.32	2.15	2.29	2.52	2.91	3.15	3.51	ns	
LVCMOS25_F16	1.08	1.16	1.32	1.92	2.17	2.45	2.68	3.03	3.44	ns	
LVCMOS18_S4	0.64	0.66	0.74	1.55	1.68	1.78	2.31	2.54	2.77	ns	
LVCMOS18_S8	0.64	0.66	0.74	2.14	2.28	2.37	2.90	3.14	3.36	ns	
LVCMOS18_S12	0.64	0.66	0.74	2.14	2.28	2.37	2.90	3.14	3.36	ns	
LVCMOS18_S16	0.64	0.66	0.74	1.49	1.62	1.72	2.25	2.48	2.71	ns	
LVCMOS18_S24 ⁽¹⁾	0.64	0.66	0.74	1.74	1.92	2.08	2.50	2.78	3.07	ns	
LVCMOS18_F4	0.64	0.66	0.74	1.38	1.51	1.61	2.14	2.37	2.60	ns	
LVCMOS18_F8	0.64	0.66	0.74	1.64	1.78	1.87	2.40	2.64	2.86	ns	
LVCMOS18_F12	0.64	0.66	0.74	1.64	1.78	1.87	2.40	2.64	2.86	ns	
LVCMOS18_F16	0.64	0.66	0.74	1.52	1.68	1.81	2.28	2.54	2.80	ns	
LVCMOS18_F24 ⁽¹⁾	0.64	0.66	0.74	1.34	1.46	1.55	2.10	2.32	2.54	ns	
LVCMOS15_S4	0.66	0.69	0.81	1.86	2.00	2.09	2.62	2.86	3.08	ns	
LVCMOS15_S8	0.66	0.69	0.81	2.05	2.18	2.28	2.81	3.04	3.27	ns	
LVCMOS15_S12	0.66	0.69	0.81	1.83	2.03	2.23	2.59	2.89	3.22	ns	
LVCMOS15_S16	0.66	0.69	0.81	1.76	1.95	2.13	2.52	2.81	3.12	ns	

Input Serializer/Deserializer Switching Characteristics

Table 24: ISERDES Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold for Control Lines					
T _{ISCKC_BITSILIP} /T _{ISCKC_BITSILIP}	BITSILIP pin setup/hold with respect to CLKDIV	0.01/0.12	0.02/0.13	0.02/0.15	ns
T _{ISCKC_CE} / T _{ISCKC_CE} ⁽²⁾	CE pin setup/hold with respect to CLK (for CE1)	0.39/-0.02	0.44/-0.02	0.63/-0.02	ns
T _{ISCKC_CE2} / T _{ISCKC_CE2} ⁽²⁾	CE pin setup/hold with respect to CLKDIV (for CE2)	-0.12/0.29	-0.12/0.31	-0.12/0.35	ns
Setup/Hold for Data Lines					
T _{ISDCK_D} / T _{ISCKD_D}	D pin setup/hold with respect to CLK	-0.02/0.11	-0.02/0.12	-0.02/0.15	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin setup/hold with respect to CLK (using IDELAY) ⁽¹⁾	-0.02/0.11	-0.02/0.12	-0.02/0.15	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin setup/hold with respect to CLK at DDR mode	-0.02/0.11	-0.02/0.12	-0.02/0.15	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin setup/hold with respect to CLK at DDR mode (using IDELAY) ⁽¹⁾	0.11/0.11	0.12/0.12	0.15/0.15	ns
Sequential Delays					
T _{ISCKO_Q}	CLKDIV to out at Q pin	0.46	0.47	0.58	ns
Propagation Delays					
T _{ISDO_DO}	D input to DO output pin	0.09	0.10	0.12	ns

Notes:

1. Recorded at 0 tap value.
2. T_{ISCKC_CE2} and T_{ISCKC_CE2} are reported as T_{ISCKC_CE}/T_{ISCKC_CE} in the timing report.

Output Serializer/Deserializer Switching Characteristics

Table 25: OSERDES Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold					
T _{OSDCK_D} /T _{OSCKD_D}	D input setup/hold with respect to CLKDIV	0.37/0.02	0.40/0.02	0.55/0.02	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input setup/hold with respect to CLK	0.49/-0.15	0.56/-0.15	0.68/-0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input setup/hold with respect to CLKDIV	0.27/-0.15	0.30/-0.15	0.34/-0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input setup/hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	ns
T _{OSCCK_S}	SR (Reset) input setup with respect to CLKDIV	0.41	0.46	0.75	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input setup/hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	ns
Sequential Delays					
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.35	0.37	0.42	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.41	0.43	0.49	ns
Combinatorial					
T _{OSDO_TTQ}	T input to TQ Out	0.73	0.81	0.97	ns

Notes:

1. T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in the timing report.

Table 27: IO_FIFO Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
IO_FIFO Clock to Out Delays					
T _{OFFCKO_DO}	RDCLK to Q outputs	0.51	0.56	0.63	ns
T _{CKO_FLAGS}	Clock to IO_FIFO flags	0.59	0.62	0.81	ns
Setup/Hold					
T _{CCK_D/T_{CKC_D}}	D inputs to WRCLK	0.43/-0.01	0.47/-0.01	0.53/-0.01	ns
T _{IFFCCK_WREN/T_{IFFCKC_WREN}}	WREN to WRCLK	0.39/-0.01	0.43/-0.01	0.50/-0.01	ns
T _{OFFCCK_RDEN/T_{OFFCKC_RDEN}}	RDEN to RDCLK	0.49/0.01	0.53/0.02	0.61/0.02	ns
Minimum Pulse Width					
T _{PWH_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	ns
T _{PWL_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	ns
Maximum Frequency					
F _{MAX}	RDCLK and WRCLK	533.05	470.37	400.00	MHz

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 29: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Sequential Delays					
T _{SHCKO} ⁽¹⁾	Clock to A – B outputs	0.68	0.70	0.85	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	ns, Min
T _{CECK_LRAM} /T _{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	ns, Min
Clock CLK					
T _{MPW}	Minimum pulse width	0.68	0.77	0.91	ns, Min
T _{MCP}	Minimum clock period	1.35	1.54	1.82	ns, Min

Notes:

1. T_{SHCKO} also represents the CLK to XMUX output. Refer to the timing report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 30: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Sequential Delays					
T _{REG}	Clock to A – D outputs	0.96	0.98	1.20	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{WS_SHFREG} /T _{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	ns, Min
T _{CECK_SHFREG} /T _{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	ns, Min
T _{DS_SHFREG} /T _{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	ns, Min
Clock CLK					
T _{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	ns, Min

Table 31: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Maximum Frequency					
F _{MAX_BRAM_WF_NC}	Block RAM (Write first and No change modes) When not in SDP RF mode	601.32	543.77	458.09	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (Read first, Performance mode) When in SDP RF mode but no address overlap between port A and port B	601.32	543.77	458.09	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (Read first, Delayed_write mode) When in SDP RF mode and there is possibility of overlap between port A and port B addresses	528.26	477.33	400.80	MHz
F _{MAX_CAS_WF_NC}	Block RAM Cascade (Write first, No change mode) When cascade but not in RF mode	551.27	493.83	408.00	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM Cascade (Read first, Performance mode) When in cascade with RF mode and no possibility of address overlap/one port is disabled	551.27	493.83	408.00	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	478.24	427.35	350.88	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	601.32	543.77	458.09	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	484.26	430.85	351.12	MHz

Notes:

1. The timing report shows all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCKO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

DSP48E1 Switching Characteristics

Table 32: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup and Hold Times of Data/Control Pins to the Input Register Clock					
$T_{DSPDCK_A_AREG}/T_{DSPCKD_A_AREG}$	A input to A register CLK	0.24/0.12	0.27/0.14	0.31/0.16	ns
$T_{DSPDCK_B_BREG}/T_{DSPCKD_B_BREG}$	B input to B register CLK	0.28/0.13	0.32/0.14	0.39/0.15	ns
$T_{DSPDCK_C_CREG}/T_{DSPCKD_C_CREG}$	C input to C register CLK	0.15/0.15	0.17/0.17	0.20/0.20	ns
$T_{DSPDCK_D_DREG}/T_{DSPCKD_D_DREG}$	D input to D register CLK	0.21/0.19	0.27/0.22	0.35/0.26	ns
$T_{DSPDCK_ACIN_AREG}/T_{DSPCKD_ACIN_AREG}$	ACIN input to A register CLK	0.21/0.12	0.24/0.14	0.27/0.16	ns
$T_{DSPDCK_BCIN_BREG}/T_{DSPCKD_BCIN_BREG}$	BCIN input to B register CLK	0.22/0.13	0.25/0.14	0.30/0.15	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock					
$T_{DSPDCK_{A,B}_MREG_MULT}/T_{DSPCKD_{A,B}_MREG_MULT}$	{A, B,} input to M register CLK using multiplier	2.04/-0.01	2.34/-0.01	2.79/-0.01	ns
$T_{DSPDCK_{A,B}_ADREG}/T_{DSPCKD_{A,B}_ADREG}$	{A, D} input to AD register CLK	1.09/-0.02	1.25/-0.02	1.49/-0.02	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock					
$T_{DSPDCK_{A,B}_PREG_MULT}/T_{DSPCKD_{A,B}_PREG_MULT}$	{A, B,} input to P register CLK using multiplier	3.41/-0.24	3.90/-0.24	4.64/-0.24	ns
$T_{DSPDCK_D_PREG_MULT}/T_{DSPCKD_D_PREG_MULT}$	D input to P register CLK using multiplier	3.33/-0.62	3.81/-0.62	4.53/-0.62	ns
$T_{DSPDCK_{A,B}_PREG}/T_{DSPCKD_{A,B}_PREG}$	A or B input to P register CLK not using multiplier	1.47/-0.24	1.68/-0.24	2.00/-0.24	ns
$T_{DSPDCK_C_PREG}/T_{DSPCKD_C_PREG}$	C input to P register CLK not using multiplier	1.30/-0.22	1.49/-0.22	1.78/-0.22	ns
$T_{DSPDCK_PCIN_PREG}/T_{DSPCKD_PCIN_PREG}$	PCIN input to P register CLK	1.12/-0.13	1.28/-0.13	1.52/-0.13	ns
Setup and Hold Times of the CE Pins					
$T_{DSPDCK_{CEA;CEB}_{AREG;BREG}}/T_{DSPCKD_{CEA;CEB}_{AREG;BREG}}$	{CEA; CEB} input to {A; B} register CLK	0.30/0.05	0.36/0.06	0.44/0.09	ns
$T_{DSPDCK_CEC_CREG}/T_{DSPCKD_CEC_CREG}$	CEC input to C register CLK	0.24/0.08	0.29/0.09	0.36/0.11	ns
$T_{DSPDCK_CED_DREG}/T_{DSPCKD_CED_DREG}$	CED input to D register CLK	0.31/-0.02	0.36/-0.02	0.44/-0.02	ns
$T_{DSPDCK_CEM_MREG}/T_{DSPCKD_CEM_MREG}$	CEM input to M register CLK	0.26/0.15	0.29/0.17	0.33/0.20	ns
$T_{DSPDCK_CEP_PREG}/T_{DSPCKD_CEP_PREG}$	CEP input to P register CLK	0.31/0.01	0.36/0.01	0.45/0.01	ns
Setup and Hold Times of the RST Pins					
$T_{DSPDCK_{RSTA;RSTB}_{AREG;BREG}}/T_{DSPCKD_{RSTA;RSTB}_{AREG;BREG}}$	{RSTA, RSTB} input to {A, B} register CLK	0.34/0.10	0.39/0.11	0.47/0.13	ns
$T_{DSPDCK_RSTC_CREG}/T_{DSPCKD_RSTC_CREG}$	RSTC input to C register CLK	0.06/0.22	0.07/0.24	0.08/0.26	ns
$T_{DSPDCK_RSTD_DREG}/T_{DSPCKD_RSTD_DREG}$	RSTD input to D register CLK	0.37/0.06	0.42/0.06	0.50/0.07	ns
$T_{DSPDCK_RSTM_MREG}/T_{DSPCKD_RSTM_MREG}$	RSTM input to M register CLK	0.18/0.18	0.20/0.21	0.23/0.24	ns
$T_{DSPDCK_RSTP_PREG}/T_{DSPCKD_RSTP_PREG}$	RSTP input to P register CLK	0.24/0.01	0.26/0.01	0.30/0.01	ns
Combinatorial Delays from Input Pins to Output Pins					
$T_{DSPDO_A_CARRYOUT_MULT}$	A input to CARRYOUT output using multiplier	3.21	3.69	4.39	ns
$T_{DSPDO_D_P_MULT}$	D input to P output using multiplier	3.15	3.61	4.30	ns

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Clock to Outs from Input Register Clock to Cascading Output Pins					
T _{DSPCKO_(ACOUT; BCOUT)_(AREG; BREG)}	CLK (ACOUT, BCOUT) to {A,B} register output	0.55	0.62	0.74	ns
T _{DSPCKO_CARRYCASOUT_{AREG, BREG}_MULT}	CLK (AREG, BREG) to CARRYCASOUT output using multiplier	3.55	4.06	4.84	ns
T _{DSPCKO_CARRYCASOUT_BREG}	CLK (BREG) to CARRYCASOUT output not using multiplier	1.60	1.82	2.16	ns
T _{DSPCKO_CARRYCASOUT_DREG_MULT}	CLK (DREG) to CARRYCASOUT output using multiplier	3.52	4.03	4.79	ns
T _{DSPCKO_CARRYCASOUT_CREG}	CLK (CREG) to CARRYCASOUT output	1.64	1.88	2.23	ns
Maximum Frequency					
F _{MAX}	With all registers used	741.84	650.20	547.95	MHz
F _{MAX_PATDET}	With pattern detector	627.35	549.75	463.61	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	412.20	360.75	303.77	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	374.25	327.65	276.01	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	468.82	408.66	342.70	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	468.82	408.66	342.58	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	306.84	267.81	225.02	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	285.23	249.13	209.38	MHz

Clock Buffers and Networks

Table 33: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BCCCK_CE} /T _{BCCKC_CE} ⁽¹⁾	CE pins setup/hold	0.12/0.30	0.14/0.38	0.26/0.38	ns
T _{BCCCK_S} /T _{BCCKC_S} ⁽¹⁾	S pins setup/hold	0.12/0.30	0.14/0.38	0.26/0.38	ns
T _{BCCKO_O} ⁽²⁾	BUFGCTRL delay from I0/I1 to O	0.08	0.10	0.12	ns
Maximum Frequency					
F _{MAX_BUFG}	Global clock tree (BUFG)	741.00	710.00	625.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCKO_O} values.

Table 34: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BLOCKO_O}	Clock to out delay from I to O	1.04	1.14	1.32	ns
Maximum Frequency					
F _{MAX_BUFIO}	I/O clock tree (BUFIO)	800.00	800.00	710.00	MHz

Table 35: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BRCKO_O}	Clock to out delay from I to O	0.60	0.65	0.77	ns
T _{BRCKO_O_BYP}	Clock to out delay from I to O with Divide Bypass attribute set	0.30	0.32	0.38	ns
T _{BRDO_O}	Propagation delay from CLR to O	0.71	0.75	0.96	ns
Maximum Frequency					
F _{MAX_BUFR} ⁽¹⁾	Regional clock tree (BUFR)	600.00	540.00	450.00	MHz

Notes:

1. The maximum input frequency to the BUFR and BUFMR is the BUFIO F_{MAX} frequency.

Table 36: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	ns
T _{BHCKC_CE} /T _{BHCKC_CE}	CE pin setup and hold	0.20/0.16	0.23/0.20	0.38/0.21	ns
Maximum Frequency					
F _{MAX_BUFH}	Horizontal clock buffer (BUFH)	741.00	710.00	625.00	MHz

Table 37: Duty Cycle Distortion and Clock Tree Skew

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
T _{DCD_CLK}	Global clock tree duty cycle distortion ⁽¹⁾	All	0.20	0.20	0.20	ns
T _{CKSKEW}	Global clock tree skew ⁽²⁾	XC7V585T	0.75	0.91	0.98	ns
		XC7V2000T	N/A	0.39	0.39	ns
		XC7VX330T	0.60	0.74	0.79	ns
		XC7VX415T	0.76	0.84	0.91	ns
		XC7VX485T	0.60	0.74	0.79	ns
		XC7VX550T	0.73	0.88	0.96	ns
		XC7VX690T	0.73	0.88	0.96	ns
		XC7VX980T	N/A	0.91	0.98	ns
		XC7VX1140T	N/A	0.39	0.39	ns
T _{DCD_BUFO}	I/O clock tree duty cycle distortion	All	0.12	0.12	0.12	ns
T _{BUFIOSKEW}	I/O clock tree skew across one clock region	All	0.02	0.02	0.02	ns
T _{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the I/O flip-flops. For all I/O standards, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements in a single SLR. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx Timing Analyzer tools to evaluate clock skew specific to your application.

MMCM Switching Characteristics

Table 38: MMCM Specification

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
MMCM_F _{INMAX}	Maximum input clock frequency	1066.00	933.00	800.00	MHz
MMCM_F _{INMIN}	Minimum input clock frequency	10	10	10	MHz
MMCM_F _{INJITTER}	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max			
MMCM_F _{INDUTY}	Allowable input duty cycle: 10—49 MHz	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	%
MMCM_F _{MIN_PSCLK}	Minimum dynamic phase shift clock frequency	0.01	0.01	0.01	MHz
MMCM_F _{MAX_PSCLK}	Maximum dynamic phase shift clock frequency	550.00	500.00	450.00	MHz
MMCM_F _{VCOMIN}	Minimum MMCM VCO frequency	600.00	600.00	600.00	MHz
MMCM_F _{VCOMAX}	Maximum MMCM VCO frequency	1600.00	1440.00	1200.00	MHz
MMCM_F _{BANDWIDTH}	Low MMCM bandwidth at typical ⁽¹⁾	1.00	1.00	1.00	MHz
	High MMCM bandwidth at typical ⁽¹⁾	4.00	4.00	4.00	MHz
MMCM_T _{STATPHAOFFSET}	Static phase offset of the MMCM outputs ⁽²⁾	0.12	0.12	0.12	ns
MMCM_T _{OUTJITTER}	MMCM output jitter	Note 3			
MMCM_T _{OUTDUTY}	MMCM output clock duty cycle precision ⁽⁴⁾	0.20	0.20	0.20	ns

Table 38: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
MMCM_T_LOCKMAX	MMCM maximum Lock Time	100	100	100	μs
MMCM_F_OUTMAX	MMCM maximum output frequency	1066.00	933.00	800.00	MHz
MMCM_F_OUTMIN	MMCM minimum output frequency ⁽⁵⁾⁽⁶⁾	4.69	4.69	4.69	MHz
MMCM_T_EXTFDVAR	External clock feedback variation	< 20% of clock input period or 1 ns Max			
MMCM_RST_MINPULSE	Minimum reset pulse width	5.00	5.00	5.00	ns
MMCM_F_PFDMAX	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	MHz
MMCM_F_PFDMIN	Minimum frequency at the phase frequency detector	10.00	10.00	10.00	MHz
MMCM_T_FBDELAY	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle			
MMCM Switching Characteristics Setup and Hold					
T_MMCM_DCK_PSEN/ T_MMCM_CKD_PSEN	Setup and hold of phase-shift enable	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_DCK_PSINCDEC/ T_MMCM_CKD_PSINCDEC	Setup and hold of phase-shift increment/decrement	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_CKO_PSDONE	Phase shift clock-to-out of PSDONE	0.59	0.68	0.81	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK					
T_MMCM_DCK_DADDR/ T_MMCM_CKD_DADDR	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T_MMCM_DCK_DI/T_MMCM_CKD_DI	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T_MMCM_DCK_DEN/T_MMCM_CKD_DEN	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	ns, Min
T_MMCM_DCK_DWE/T_MMCM_CKD_DWE	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	ns, Min
T_MMCM_CKO_DRDY	CLK to out of DRDY	0.65	0.72	0.99	ns, Max
F_DCK	DCLK frequency	200.00	200.00	200.00	MHz, Max

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.
6. When CLKOUT4_CASCADE = TRUE, MMCM_F_OUTMIN is 0.036 MHz.

Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 45: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks (only)

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾						
T_{PSFD}/T_{PHFD}	Full delay (legacy delay or default delay) Global clock Input and IFF ⁽²⁾ without MMCM/PLL with ZHOLD_DELAY on HR I/O banks	XC7V585T	3.12/-0.37	3.19/-0.37	3.42/-0.37	ns
		XC7V2000T	N/A	N/A	N/A	ns
		XC7VX330T	2.90/-0.31	2.96/-0.31	3.16/-0.31	ns
		XC7VX415T	N/A	N/A	N/A	ns
		XC7VX485T	N/A	N/A	N/A	ns
		XC7VX550T	N/A	N/A	N/A	ns
		XC7VX690T	N/A	N/A	N/A	ns
		XC7VX980T	N/A	N/A	N/A	ns
		XC7VX1140T	N/A	N/A	N/A	ns

Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch

Table 46: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾⁽²⁾						
$T_{PSMMCMCC}/T_{PHMMCMCC}$	No delay clock-capable clock input and IFF ⁽³⁾ with MMCM	XC7V585T	2.71/-0.10	3.00/-0.10	3.33/-0.10	ns
		XC7V2000T	N/A	2.60/-0.24	2.87/-0.24	ns
		XC7VX330T	2.58/-0.15	2.87/-0.15	3.18/-0.15	ns
		XC7VX415T	2.73/0.01	3.03/0.01	3.36/0.01	ns
		XC7VX485T	2.58/-0.15	2.87/-0.15	3.18/-0.15	ns
		XC7VX550T	2.72/-0.09	3.01/-0.09	3.34/-0.09	ns
		XC7VX690T	2.72/0.01	3.01/0.01	3.34/0.01	ns
		XC7VX980T	N/A	3.01/-0.10	3.36/-0.10	ns
		XC7VX1140T	N/A	2.61/-0.24	2.88/-0.24	ns

Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net in a single SLR.
3. IFF = Input Flip-Flop or Latch
4. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-7 T and XT FPGA clock transmitter and receiver data-valid windows.

Table 50: Package Skew

Symbol	Description	Device	Package	Value	Units
$T_{PKGSKEW}$	Package Skew ⁽¹⁾	XC7V585T	FFG1157	232	ps
			FFG1761	255	ps
		XC7V2000T	FHG1761	308	ps
			FLG1925	266	ps
		XC7VX330T	FFG1157	170	ps
			FFG1761	270	ps
		XC7VX415T	FFG1157	203	ps
			FFG1158	237	ps
			FFG1927	183	ps
		XC7VX485T	FFG1157	191	ps
			FFG1158	209	ps
			FFG1761	274	ps
			FFG1927	209	ps
			FFG1930	304	ps
		XC7VX550T	FFG1158	217	ps
			FFG1927	254	ps
		XC7VX690T	FFG1157	239	ps
			FFG1158	217	ps
			FFG1761	284	ps
			FFG1926	238	ps
			FFG1927	254	ps
			FFG1930	287	ps
		XC7VX980T	FFG1926	242	ps
			FFG1928	199	ps
			FFG1930	243	ps
		XC7VX1140T	FLG1926	271	ps
			FLG1928	216	ps
			FLG1930	279	ps

Notes:

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
2. Package delay information is available for these device/package combinations. This information can be used to deskew the package.

Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-3 speed grade	60	—	700	MHz
		All other speed grades	60	—	670	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

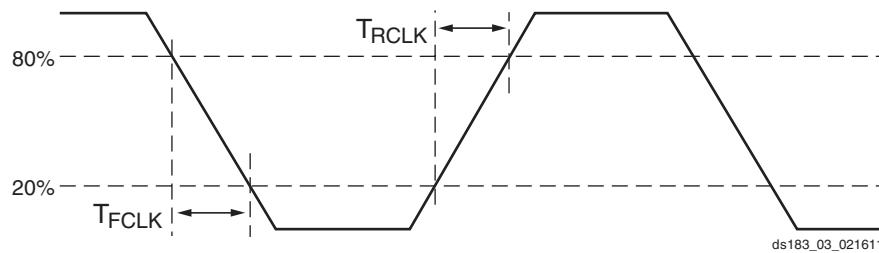


Figure 3: Reference Clock Timing Parameters

Table 56: GTX Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock		—	—	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	37×10^6	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		—	50,000	2.3×10^6	UI

Table 57: GTX Transceiver User Clock Switching Characteristics⁽¹⁾⁽²⁾

Symbol	Description	Data Width Conditions		Speed Grade			Units
		Internal Logic	Interconnect Logic	-3/-2G ⁽³⁾	-2/-2L ⁽³⁾	-1 ⁽⁴⁾	
F _{TXOUT}	TXOUTCLK maximum frequency			412.500	412.500	312.500	MHz
F _{RXOUT}	RXOUTCLK maximum frequency			412.500	412.500	312.500	MHz
F _{TXIN}	TXUSRCLK maximum frequency	16-bit	16-bit and 32-bit	412.500	412.500	312.500	MHz
		32-bit	32-bit	390.625	322.266	250.000	MHz
F _{RXIN}	RXUSRCLK maximum frequency	16-bit	16-bit and 32-bit	412.500	412.500	312.500	MHz
		32-bit	32-bit	390.625	322.266	250.000	MHz
F _{TXIN2}	TXUSRCLK2 maximum frequency	16-bit	16-bit	412.500	412.500	312.500	MHz
		16-bit and 32-bit	32-bit	390.625	322.266	250.000	MHz
		64-bit	64-bit	195.313	161.133	125.000	MHz
F _{RXIN2}	RXUSRCLK2 maximum frequency	16-bit	16-bit	412.500	412.500	312.500	MHz
		16-bit and 32-bit	32-bit	390.625	322.266	250.000	MHz
		64-bit	64-bit	195.313	161.133	125.000	MHz

Notes:

1. Clocking must be implemented as described in the 7 Series FPGAs GTX/GTH Transceiver User Guide ([UG476](#)).
2. These frequencies are not supported for all possible transceiver configurations.
3. For speed grades -3, -2, -2L, and -2G, a 16-bit data path can only be used for speeds less than 6.6 Gb/s.
4. For speed grade -1, a 16-bit data path can only be used for speeds less than 5.0 Gb/s. For speed grade -1C with V_{CCINT} = 0.9V, as described in the *Lowering Power using the Voltage Identification Bit* application note ([XAPP555](#)), a 16-bit data path can only be used for speeds less than 3.8 Gb/s.

Table 58: GTX Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTXTX}	Serial data rate range		0.500	–	F _{GTXMAX}	Gb/s
T _{RTX}	TX rise time	20%–80%	–	40	–	ps
T _{FTX}	TX fall time	80%–20%	–	40	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	500	ps
V _{TXOOBVDP}	Electrical idle amplitude		–	–	15	mV
T _{TXOOBTRANSITION}	Electrical idle transition time		–	–	140	ns
TJ _{12.5}	Total jitter ⁽²⁾⁽⁴⁾	12.5 Gb/s	–	–	0.28	UI
DJ _{12.5}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{11.18}	Total jitter ⁽²⁾⁽⁴⁾	11.18 Gb/s	–	–	0.28	UI
DJ _{11.18}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{10.3125}	Total jitter ⁽²⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.28	UI
DJ _{10.3125}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{9.953}	Total jitter ⁽²⁾⁽⁴⁾	9.953 Gb/s	–	–	0.28	UI
DJ _{9.953}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{9.8}	Total jitter ⁽²⁾⁽⁴⁾	9.8 Gb/s	–	–	0.28	UI
DJ _{9.8}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{8.0}	Total jitter ⁽²⁾⁽⁴⁾	8.0 Gb/s	–	–	0.30	UI
DJ _{8.0}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.15	UI
TJ _{6.6_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	6.6 Gb/s	–	–	0.28	UI
DJ _{6.6_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI

Table 59: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.500	—	F_{GTXMAX}	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		—	10	—	ns
RX_{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX_{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	0	ppm
RX_{RL}	Run length (CID)		—	—	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	-1250	—	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	-700	—	700	ppm
		Bit rates > 8.0 Gb/s	-200	—	200	ppm
SJ Jitter Tolerance⁽²⁾						
$JT_{SJ12.5}$	Sinusoidal jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	—	—	UI
$JT_{SJ11.18}$	Sinusoidal jitter (QPLL) ⁽³⁾	11.18 Gb/s	0.3	—	—	UI
$JT_{SJ10.32}$	Sinusoidal jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
$JT_{SJ9.95}$	Sinusoidal jitter (QPLL) ⁽³⁾	9.95 Gb/s	0.3	—	—	UI
$JT_{SJ9.8}$	Sinusoidal jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	—	—	UI
$JT_{SJ8.0}$	Sinusoidal jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	—	—	UI
$JT_{SJ6.6_QPLL}$	Sinusoidal jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	—	—	UI
$JT_{SJ6.6_CPLL}$	Sinusoidal jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	—	—	UI
$JT_{SJ5.0}$	Sinusoidal jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
$JT_{SJ4.25}$	Sinusoidal jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
$JT_{SJ3.75}$	Sinusoidal jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
$JT_{SJ3.2}$	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	—	—	UI
$JT_{SJ3.2L}$	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	—	—	UI
$JT_{SJ2.5}$	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	—	—	UI
$JT_{SJ1.25}$	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	—	—	UI
JT_{SJ500}	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
$JT_{TJSE3.2}$	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
$JT_{TJSE6.6}$		6.6 Gb/s	0.70	—	—	UI
$JT_{SJSE3.2}$	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.1	—	—	UI
$JT_{SJSE6.6}$		6.6 Gb/s	0.1	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX equalizer enabled. DFE disabled.

Table 74: GTH Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTHRX}	Serial data rate	RX oversampler not enabled	0.500	—	F _{GTHMAX}	Gb/s
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		—	10	—	ns
RX _{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	0	ppm
RX _{RL}	Run length (CID)		—	—	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	-1250	—	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	-700	—	700	ppm
		Bit rates > 8.0 Gb/s	-200	—	200	ppm
SJ Jitter Tolerance⁽²⁾						
JT_SJ _{13.1}	Sinusoidal jitter (QPLL) ⁽³⁾	13.1 Gb/s	0.3	—	—	UI
JT_SJ _{12.5}	Sinusoidal jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	—	—	UI
JT_SJ _{11.3}	Sinusoidal jitter (QPLL) ⁽³⁾	11.3 Gb/s	0.3	—	—	UI
JT_SJ _{10.32_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
JT_SJ _{10.32_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
JT_SJ _{9.8}	Sinusoidal jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	—	—	UI
JT_SJ _{8.0_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	—	—	UI
JT_SJ _{8.0_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	8.0 Gb/s	0.42	—	—	UI
JT_SJ _{6.6_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	—	—	UI
JT_SJ _{6.6_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	—	—	UI
JT_SJ _{5.0}	Sinusoidal jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
JT_SJ _{4.25}	Sinusoidal jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
JT_SJ _{3.75}	Sinusoidal jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
JT_SJ _{3.2}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	—	—	UI
JT_SJ _{3.2L}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	—	—	UI
JT_SJ _{2.5}	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	—	—	UI
JT_SJ _{1.25}	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	—	—	UI
JT_SJ ₅₀₀	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
JT_TJSE _{3.2}	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
JT_TJSE _{6.6}		6.6 Gb/s	0.70	—	—	UI
JT_SJSE _{3.2}	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.1	—	—	UI
JT_SJSE _{6.6}		6.6 Gb/s	0.1	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX equalizer enabled. DFE disabled.